

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	0	(yield adj (enhancement or improvement)) and ((physical adj defect\$2) same substrate) and ((binding or grouping) adj structure) and (design adj (information or data or specification)) and (location)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/05 11:45
L2	0	(yield adj (enhancement or improvement)) and ((physical adj defect\$2) same substrate) and ((binning or grouping) adj structure) and (design adj (information or data or specification)) and (location)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/05 11:03
L3	0	(yield adj (enhancement or improvement)) and ((physical adj defect\$2) same substrate) and ((binning or grouping) adj structures) and (design adj (information or data or specification)) and (location)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/05 11:04
L4	2	(yield adj (enhancement or improvement)) and ((physical adj defect\$2) same substrate) and (design adj (information or data or specification)) (classes adj (physical adj structure)) and (location)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/05 11:07
L5	0	((yield adj (enhancement or improvement)) and ((physical adj defect\$2) same substrate) and (design adj (information or data or specification)) (classes adj (physical adj structure)) and (location)).CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/05 11:08
L6	0	((yield adj (enhancement or improvement)) and ((physical adj defect\$2) and substrate) and (design same (information or data or specification)) (classes same (physical adj structure)) and (location)).CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/05 11:08
L7	27	((yield adj (enhancement or improvement)) and ((physical adj defect\$2) and substrate) and (design same (information or data or specification)) (classes same (physical adj structure)) and (location))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/05 11:08

L8	2384	716/4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/05 11:46
L9	0	(716/4).ccls. and (yield adj (enhancement or improvement)) and ((physical adj defect\$2) same (substrate or wafer)) and (design adj (information or data))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/05 11:49
L10	1	(716/4).ccls. and (yield adj (enhancement or improvement)) and ((physical adj defect\$2) same (substrate or wafer)) and (design adj (information or data))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/05 11:49
S1	1134	716/19	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/05 10:13
S2	816	716/21	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/05 10:13
S3	1909	716/1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/05 10:13
S4	1650	716/2	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/05 10:13
S5	0	(716/19).ccls. and (yield adj (enhancement or improvement)) and ((physical adj defect\$2) same substrate) and (design adj (information or data or specification))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/05 10:16
S6	0	(716/21).ccls. and (yield adj (enhancement or improvement)) and ((physical adj defect\$2) same substrate) and (design adj (information or data or specification))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/05 10:16

S7	0	(716/1).ccls. and (yield adj (enhancement or improvement)) and ((physical adj defect\$2) same substrate) and (design adj (information or data or specification))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/05 10:16
S8	0	(716/2).ccls. and (yield adj (enhancement or improvement)) and ((physical adj defect\$2) same substrate) and (design adj (information or data or specification))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/05 10:16
S9	1	("716"/\$).ccls. and (yield adj (enhancement or improvement)) and ((physical adj defect\$2) same substrate) and (design adj (information or data or specification))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/05 10:21
S10	1	(yield adj (enhancement or improvement)) and ((physical adj defect\$2) same substrate) and (design adj (information or data or specification))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/05 10:22

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IEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IEE CNF IEE Conference Proceeding

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- 1. Analysis of defect to yield correlation on memories: method, algorithms :**
Bichebois, P.; Mathery, P.;
Defect and Fault Tolerance in VLSI Systems, 1997. Proceedings., 1997 IEEE I
Symposium on
20-22 Oct. 1997 Page(s):44 - 52
Digital Object Identifier 10.1109/DFTVS.1997.628308
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- 2. Wafer back side inspection applications for yield protection and enhance**
Cheema, L.A.; Olmer, L.J.; Patterson, O.D.; Lopez, S.S.; Burns, M.B.;
Advanced Semiconductor Manufacturing 2002 IEEE/SEMI Conference and Workshops
30 April-2 May 2002 Page(s):64 - 71
Digital Object Identifier 10.1109/ASMC.2002.1001576
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